

MTU_MBIST_1

for KIT_AURIX_TC297_TFT

Memory Built-In Test via MTU

AURIX™ TC2xx Microcontroller Training
V1.0.2



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Scope of work

The MBIST is used to assess the state of the memory.

In this training the Memory Test Unit (MTU) is used to initialize and clear the content of an SRAM memory including its ECC code. Also, the non destructive inversion test is performed by Memory Built-in-Self-Test (MBIST) to verify the content of the same SRAM memory.

The SRAM of the DMA (DMARAM) is selected to be tested in this example. In order to test the faulty scenario, this training provides the possibility to inject a single bit error in the memory.

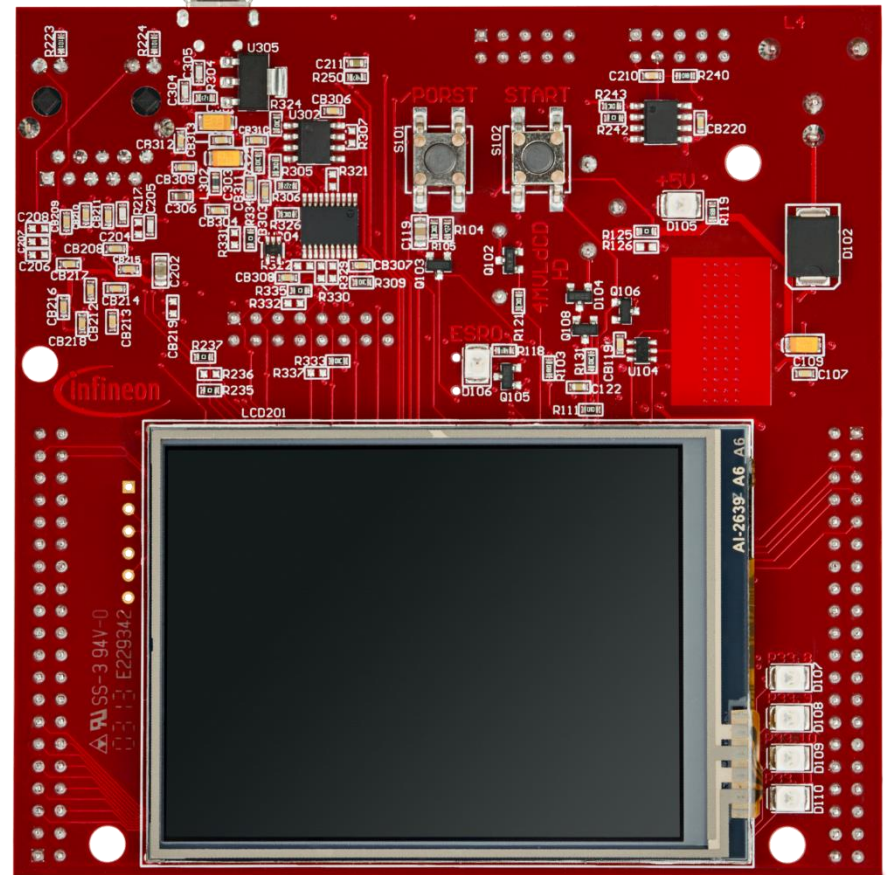
The LEDs on the board are used to signal the correct or faulty behavior of the MBIST.

Introduction

- › The Memory Test Unit (MTU) is the unified interface for the control of ECC (Error Correction), BIST (Built-in-Self-Test) and redundancy features for the internal memories within the AURIX™ TC2xx family of microcontrollers.
- › The Memory Built-in-Self-Test (MBIST) is an MTU feature, which enables the verification of the integrity of internal SRAMs. At least one MBIST is available per SRAM.
- › MBIST has a direct data memory access capability via the Memory Controllers (MCs), which enables the reading and writing of data together with its ECC code.

Hardware setup

This code example has been developed for the board
KIT_AURIX_TC297_TFT_BC-Step.



Implementation

MBIST test implementation:

- › Execution of the MBIST test is ensured by the ***test_MTU_MBIST()*** function, containing the following steps:
 1. MTU module is enabled:
IfxMtu_enableModule()
 2. The SRAM to be tested is initialized using MTU:
IfxMtu_clearSram()
 3. Optionally, an error is injected before test execution (Please refer to [next slide](#))
 4. The non destructive inversion test is triggered:
IfxMtu_runNonDestructiveInversionTest()
 5. After test completion, the ***IfxMtu_runNonDestructiveInversionTest()*** function returns whether the RAM content is correct or an error is detected.

- › The functions above are provided by the iLLD header ***IfxMtu.h***.

Note: In this training, the DMARAM is tested by calling ***test_MTU_MBIST(ifxMtu_MbistSel_dma)*** in the main function. It is possible to test any other SRAM memory ***X*** by calling ***test_MTU_MBIST(ifxMtu_MbistSel_X)***.

Implementation

Correctable Error Injection:

The error injection option can be enabled by setting the global variable ***g_errorInjection*** to ***TRUE*** in ***MBIST_MTU.c*** file.

Implementation steps:

1. Safety Endinit protection is cleared: ***IfxScuWdt_clearSafetyEndinit()***
 2. MBIST controller is enabled: ***IfxMtu_enableMbistShell()***
 3. Wait for the end of SRAM initialization, in case it is an auto-initialization memory:
IfxMtu_isAutoInitRunning()
 4. One memory address (Ex. 0x1F) is read: ***IfxMtu_readSramAddress()***
 5. Only one bit should be modified to inject a correctable error. DMARAM is **SEDED** (Single Error Correction, Double Error Detection)
 6. The updated memory is written back to the same address (0x1F):
IfxMtu_writeSramAddress()
 7. MBIST controller is disabled: ***IfxMtu_disableMbistShell()***
 8. Safety Endinit protection is restored: ***IfxScuWdt_setSafetyEndinit()***
- › The functions above are provided by the iLLD headers ***IfxMtu.h*** and ***IfxScuWdt.h***

Implementation

LED initialization and control:

- › Two LEDs are used in this training to report the execution of the test
 - **LED_PASS**: LED driven by port 13 pin 0
 - **LED_FAIL** : LED driven by port 13 pin 1

- › Ports configuration in the right mode to control LEDs:
 - ***IfxPort_setPinMode()***

- › LEDs control (LEDs are low-level active)
 - Switch On: ***IfxPort_setPinLow()***
 - Switch Off: ***IfxPort_setPinHigh()***

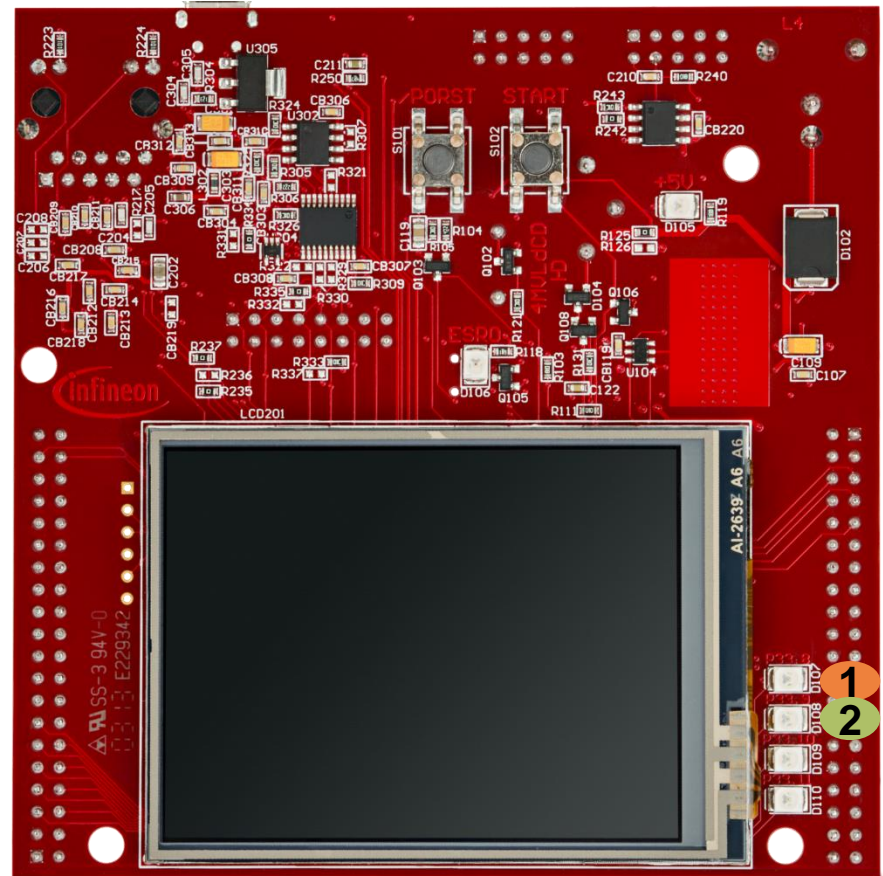
- › The functions above are provided by the iLLD header ***IfxPort.h***

Run and Test

After code compilation and flashing the device, check the behavior of **LED_PASS** (1) and **LED_FAIL** (2):

| MBIST of DMARAM | | 1 | 2 |
|-------------------|------------------------|----------|----------|
| | | LED PASS | LED FAIL |
| No Error injected | No Error detected | LED On | LED Off |
| | Error detected | LED Off | LED On |
| Error injected | No Error detected | LED Off | LED On |
| | Wrong Error detected | LED Off | LED On |
| | Correct Error detected | LED On | LED Off |

■ LED On
 ■ LED Off



References



- › AURIX™ Development Studio is available online:
- › <https://www.infineon.com/aurixdevelopmentstudio>
- › Use the „*Import...*“ function to get access to more code examples.



- › More code examples can be found on the GIT repository:
- › https://github.com/Infineon/AURIX_code_examples



- › For additional trainings, visit our webpage:
- › <https://www.infineon.com/aurix-expert-training>



- › For questions and support, use the AURIX™ Forum:
- › <https://www.infineonforums.com/forums/13-Aurix-Forum>

Revision history

| Revision | Description of change |
|-----------------|---|
| V1.0.2 | Update of version to be in line with the code example's version |
| V1.0.1 | Update of version to be in line with the code example's version |
| V1.0.0 | Initial version |
| | |

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